

Component & Device Parameter Test Instruments

I. TH2829X Series Automatic Transformer Test System



Features

- 7-inch TFT LCD display with a resolution of 800×RGB×480
- Frequency up to 1MHz, resolution: 0.5mHz
- Signal level: 5mV-2Vrms, optional (2Vrms-10Vrms)
- Built-in 0-100mA/0-10V bias power supply, optional 1A/2A bias current source
- Up to 75 times / sec test speed
- Diode forward and reverse characteristic detection
- Improved high turns ratio and weakly coupled transformer test capability
- Improved DCR testing capabilities
- Single screen can accommodate all scan test results
- Time stamping system: memory file setting, calibration deviation and deduction time
- Sort the selected scanning parameters
- Self-test scanning fixture relays
- Flexible deviation deduction method
- Multiple handling ways for FAIL cases
- Single parameter test cycle to test independent windings
- Increased security: administrator and operator passwords
- Built-in statistical analysis capabilities: Cpk, Cp, Ck, etc.
- Bar-code reading function can be used to select a setting file or to manage the type of test products
- Optional PC-level instrument test setup file programming capability
- Online upgrade mode: USBHOST or RS232
- Support multiple instrument networking through LAN interface
- Backward compatible with TH2818X/TH2819X parameter setting file
- Storage: Internal: 100 groups of settings file to save
U disk: 500 groups of configuration files, CSV format test data, GIF format images



TH2829X Series

GPIB option	RS485 option	HANDER option
RS232 standard	LAN standard	SCANNER standard
	USB HOST standard	USB DEVICE standard



TH1901B

Dimension(mm): 400mm(W)x132mm(H)x385mm(D)
Weight: 13kg

Applications

- Switching transformer scanning test, comprehensive characteristics analysis.
- Network transformer scanning test, comprehensive characteristics analysis
- Discrete passive components (L, R, C) multi-channel scanning test
- Relay drive line package, contact resistance multi-channel scanning test
- Multi-channel DC resistance DCR scanning test
- Comprehensive test analysis of multiple passive components in impedance network

Specifications

Model	TH2829AX	TH2829CX
Test Pin(PIN)	20	20
Test frequency	20Hz — 200kHz	20Hz — 1MHz
Display	800×RGB×480 7 inch TFT LCD display	
LCR Function	option	
Transformer test parameters	Turn Ratio	Turns Phase L C Lk Q ACR DCR Balance Pin Short Diode P/N
LCR test parameters	Z , Y , C, L, X, B, R, G, D, Q, θ , DCR, Turn-Ratio, Phase, Lk	
Basic test accuracy	LCRZ	0.05%
	DCR, Turn Ratio	0.1%
Signal source output impedance	10 Ω , 30 Ω , 50 Ω , 100 Ω	
Test speed (ms/times)	13ms, 90 ms, 370 ms	
AC signal level	5mVrms — 2Vrms(transformer test, can be customized to 10Vrms), 5mVrms — 10Vrms(LCR function); 50 μ Arms — 100mArms	
DC bias voltage source	----- 0V — $\pm$ 10V; 0mA — $\pm$ 100mA	
DC bias current source	0 — $\pm$ 1A option(option TH2901) / 0 — $\pm$ 2A option(option TH2902)	
DC constant current source	0mA — $\pm$ 120mA for diode forward characteristic test	
Diode test	forward test voltage	0 — 9.9999 V
	Reverse test current	0 — 99.999 mA
Comparator	10 bins, PASS/FAIL indication, file counting function	
Storage	Internal: 100 sets of configuration file;	
	U disk: 500 sets of configuration files, CSV format test data, GIF format images	